IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant:	Bhushan L. Sopori)	Atty Dkt No. NREL 02-15
Serial No.:	10/535,291)	Group Art: 1797
Filing Date:	May 16, 2005)	Examiner: Samuel P. Siefke
Title:	Wafer Characteristics Via Reflectometry))	Conf. No: 5821

MAIL STOP: AMENDMENT Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Dear Sir:

In response to the Office Action of October 29, 2008, please amend the above-identified application as follows:

Amendments to the Claims are reflected in the listing of claims beginning on page 2 of this paper.

Remarks/Arguments begin on page 8 of this paper.